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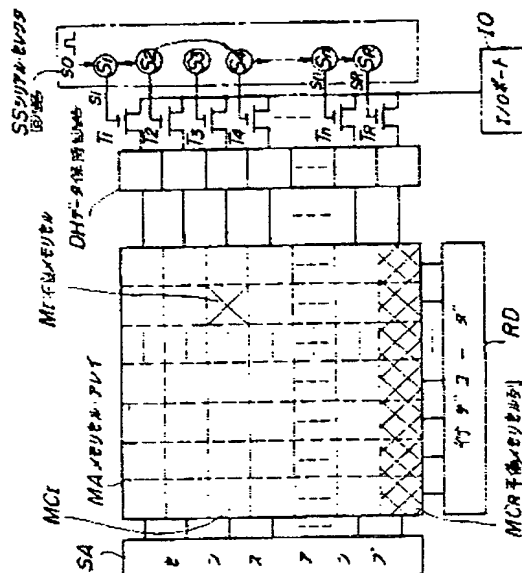
APPLICATION DATE : 12-11-87
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APPLICANT : SHARP CORP;

INVENTOR : MATSUURA YOSHIKI;

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TITLE : SEMICONDUCTOR INTEGRATED
CIRCUIT DEVICE



ABSTRACT : PURPOSE: To reduce a defective generating rate by constituting the selected circuit with the switching of a defective selected circuit to a normal selected circuit when the defective selected circuit exists in the plural selected circuits.

CONSTITUTION: When a defective memory MI exists at a position shown in a figure, the fuse link of a selector S_3 corresponding to a memory cell array MCI to which the defective memory cell belongs is disconnected. Further, the fuse link of a spare selector SR is disconnected. Thus, the selective signal is outputted as $S_1 \rightarrow S_2 \rightarrow S_4 \rightarrow SR$, the memory cell array MCI to which the defective memory cell MI belongs is jumped off, and a spare memory cell array MCR is selected instead of it. Thus, the defective generating rate can be reduced.

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